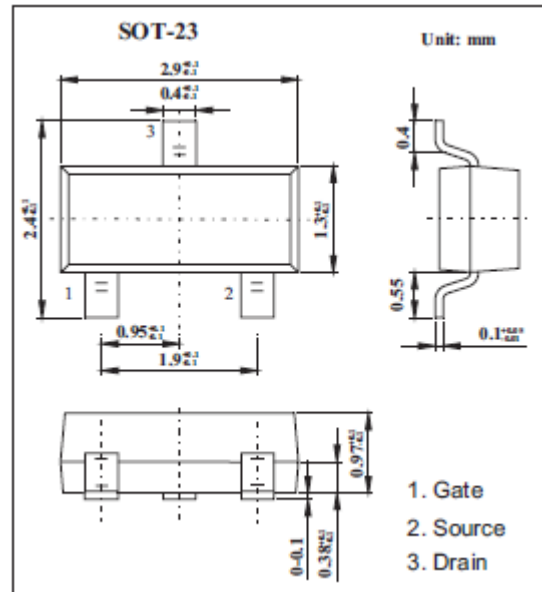
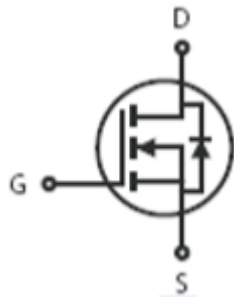


N-Channel Power MOSFET

SI2310

■ **Features**

- ◆ Simple Drive Requirement
- ◆ Small Package Outline
- ◆ Surface Mount Device



■ **Absolute Maximum Ratings Ta=25°C**

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V _{DS}	60	V
Gate-Source Voltage	V _{GS}	±20	V
Drain-Current -Continuous	I _D	T _A =25°C	A
		T _A =70°C	
Pulsed Drain Current *	I _{DM}	10	
Power Dissipation*	PD	1.25	W
Thermal Resistance, Junction-to-Ambient	R _{thJA}	100	°C/W
Operating Junction and Storage Temperature Range	T _j , T _{stg}	-55 to 150	°C

* 2.Pulse width ≤300us , duty cycle ≤ 2%

■ Electrical Characteristics Ta=25°C

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V _{DSS}	V _{GS} =0V, I _D =250uA	60			V
Zero Gate Voltage Drain Current	I _{DSS}	V _D =60V, V _{GS} =0V			10	uA
Gate-Body Leakage	I _{GSS}	V _{GS} =±20V, V _D =0V			±100	nA
Gate Threshold Voltage*	V _{GS(th)}	V _{GS} =V _D , I _D =250uA	1		3	V
Drain-Source On-state Resistance*	R _{DS(ON)}	V _{GS} =10V, I _D =3A			90	mΩ
		V _{GS} =4.5V, I _D =2A			120	mΩ
Forward Transconductance*	g _{FS}	V _D =4.5V, I _D =3A		5		S
Input Capacitance	C _{ISS}	V _D =25V, V _{GS} =0V, f=1.0MHz		490	780	pF
Output Capacitance	C _{OSS}			55		
Reverse Transfer Capacitance	C _{RSS}			40		
Turn-On Delay Time	t _{D(on)}	V _{GS} =10V, V _D =30V, I _D =1A, R _L =30Ω, V _{GEN} =3.3Ω		6		ns
Rise Time	t _r			5		
Turn-Off Delay Time	t _{D(off)}			16		
Fall Time	t _f			3		
Total Gate Charge	Q _g	V _D =48V, I _D =3A, V _{GS} =4.5V		6	10	nC
Gate-Source Charge	Q _{gs}			1.6		
Gate-Drain Charge	Q _{gd}			3		
Body Diode Reverse Recovery Time	T _{rr}	I _s =3A, di/dt=100A/us		25		nC
Diode Forward Voltage	V _{SD}	V _{GS} =0V, I _s =1.2A			1.2	V

*Pulse Test: Pulse Width ≤300μs, Duty Cycle≤2%

■ Electrical Characteristics Ta=25°C

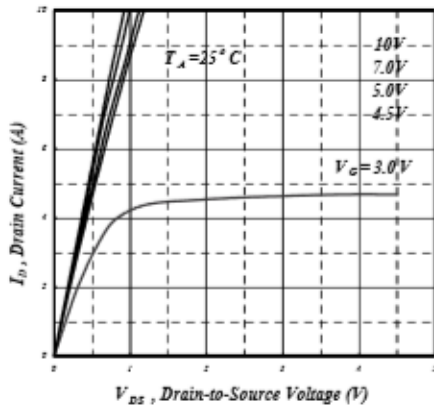


Fig 1. Typical Output Characteristics

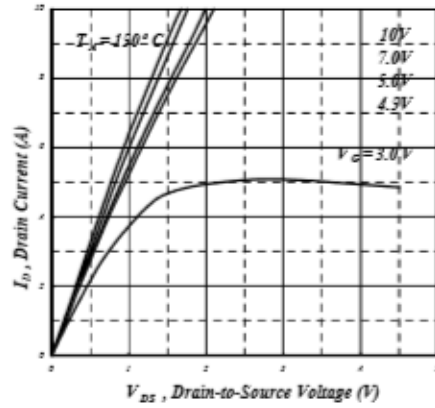


Fig 2. Typical Output Characteristics

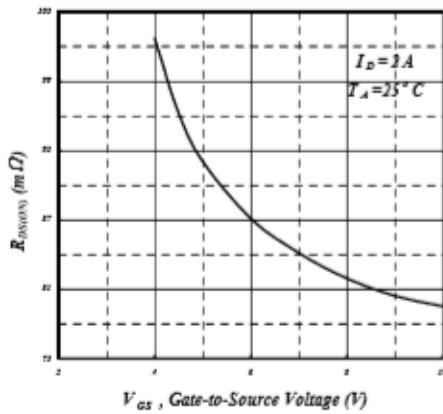


Fig 3. On-Resistance v.s. Gate Voltage

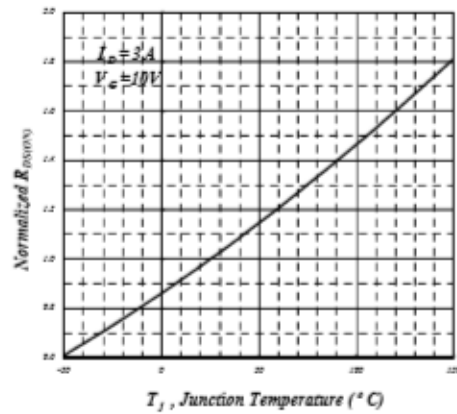


Fig 4. Normalized On-Resistance v.s. Junction Temperature

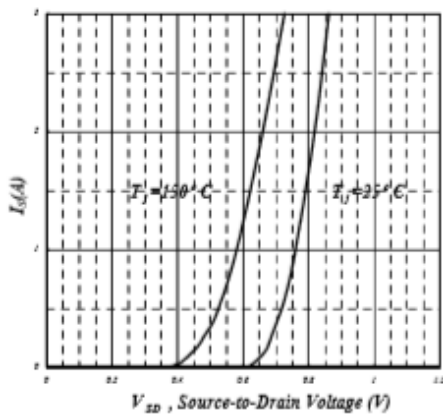


Fig 5. Forward Characteristic of Reverse Diode

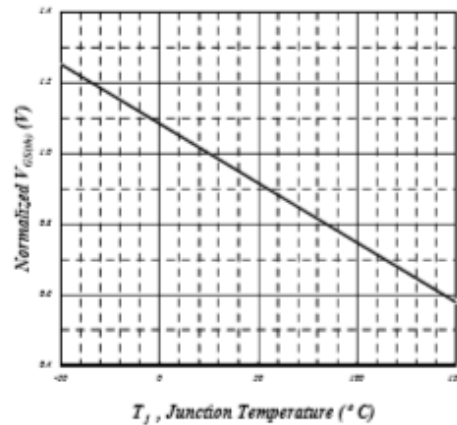


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

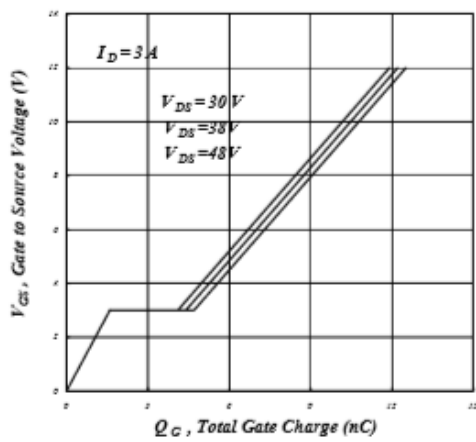


Fig 7. Gate Charge Characteristics

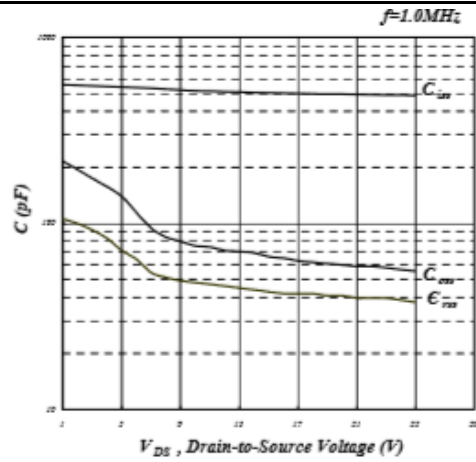


Fig 8. Typical Capacitance Characteristics

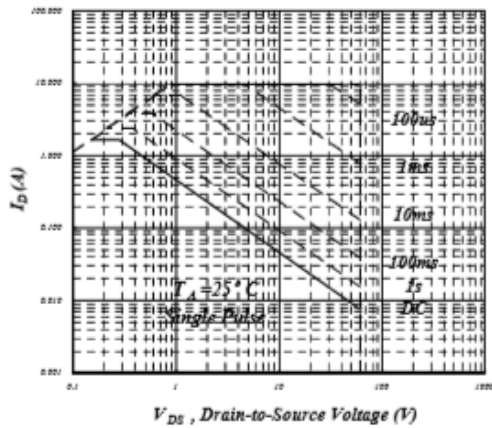


Fig 9. Maximum Safe Operating Area

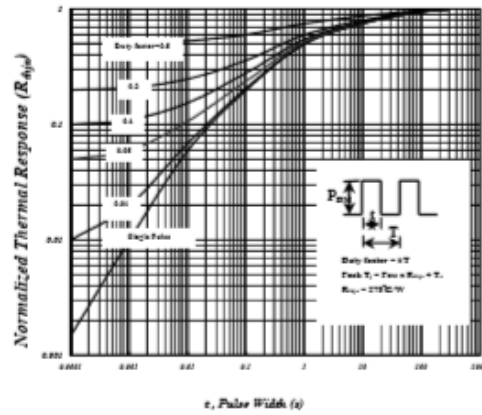


Fig 10. Effective Transient Thermal Impedance